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## THIS TECHNOLOGY IS CURRENTLY NOT AVAILABLE FOR LICENSING

Tech ID: 33172



## ADDITIONAL TECHNOLOGIES BY THESE INVENTORS

- ▶ Apodization Specific Peak Fitting In Charge Detection Mass Spectrometry
- ▶ High Performance Charge Detection Mass Spectrometry Without Ultra-High Vacuum
- ► Multiplex Charge Detection Mass Spectrometry
- ▶ Sequential Pass Express Charge Detection Mass Analyzer
- Ambient infrared laser ablation mass spectrometry (AIRLAB-MS) with plume capture by continuous flow solvent probe
- ▶ Aerosol Ionization For Charge Detection Mass Spectrometry Ion Mobility Analysis



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